Status of the Test-Station for Silicon-Strip-Detectors in Bonn

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Table of Contents

Bonn Test-Station
Tracking-Station
New Mezzanine ADC
Sensor Test @ ELSA with photons

Lab Setup in Bonn

Si-strip sensor box with Supply Board
VME-Crate with FPGA Board
New Mezzanine 65MSPS ADC

· PC



Sensor-L-Boards

L-shape for double sided mounting
Sensor ⇒ Pitch Adaptor
⇒ Front-Ends (APV25)



 Sensor: Size 2x2 cm², Pitch 50µm, 385 strips (n-side), 385 strips (p-side)





- Analog data from APVs sampled by the ADC
- ADC data stored in FIFO
- FIFO readout from VME-CPU
- Process sends data via Ethernet to PC

Channel View

100

Beadout rate: 0.63

Pedestals/Noise

Data Analysis

- Supply Board voltages
- Front-End parameters
- · Noise, pedestals, hit pattern
- Pulseheight-Spectrum
- Continuous updates from Bonn, Dresden & Mainz using common code repository



13.000

Reset

- D ×

panda CStatus

Trigger Statu initialized DAQ Status connected voltage (top) VDD 2.487

VDD/2 1,246

VDD 2,495

VDD/2 1246

FoTemp: --°C TempIC: --°C

> Softrese Trigger

Calibration Trigg

HISKP

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France

um hits over threshold 4 🚊

Trigger/Clock | Gage | VME | Scans | Evalu

Tracking-Station



- Four sensor boxes for tracking
- · x-y-z movement
- Measurement of multiple scattering for various materials
- Possible operation @ ELSA, COSY, GSI ...

New Mezzanine ADC





- ADC output written to FIFOs in FPGA
- FPGA readout via VME
- Transfer from VME crate to PC via Ethernet
- Next: FPGA based pedestal subtraction, hitfinder, noise...

Setup behind Crystal Barrel



Goals:

First test with photons (up to 2.35GeV) from an accelerator
Observation of the leakage current in the sensor

- (temperature & photon flux dependency)
- Monitoring data outside the lab (Energy-loss, noise & channel positions with photons)

Results:

- Sensor survived & operated well
- · Leakage current behaves as expected

Hits on the sensor: simulation vs. measurement



Measured energy loss:



Leakage current and ...

...photon count

temperature



Measured and predicted temperature dependend part of leakage current

Normalized leakage current and photon count



Summary / What's next?

Summary:

Modular test setup for Si-strip sensors
Full DAQ / preprocessing / reconstruction chain works

What's next?

Implement double sided sensor boards in our test setup
Construct a Tracking-Station & modify the DAQ for tracking